

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	(topography and leaky and layer).clm.	US-PGPUB	OR	ON	2006/02/13 13:19
L2	36	(minimum and residual and force).clm.	US-PGPUB	OR	ON	2006/02/13 13:20
L3	1	(minimum and residual and force and chuck).clm.	US-PGPUB	OR	ON	2006/02/13 13:20
S1	0	"Clamping and De-clamping Semiconductor Wafers on an Electrostatic Chuck Using Wafer Medial Confinement by Applying a Single-phase Square wave AC Clamping Voltage"	US-PGPUB	OR	ON	2005/03/03 09:42
S2	0	"Clamping and De-clamping Semiconductor Wafers"	US-PGPUB	OR	ON	2005/03/03 09:42
S3	0	"Clamping and De-clamping "	US-PGPUB	OR	ON	2005/03/03 09:43
S4	30190	Clamping	US-PGPUB	OR	ON	2005/03/03 09:42
S5	12	De adj clamping	US-PGPUB	OR	ON	2005/03/03 09:46
S6	0	(QIN and KELLERMAN).in.	US-PGPUB	OR	ON	2005/03/03 09:46
S7	309	(QIN KELLERMAN).in.	US-PGPUB	OR	ON	2005/03/03 09:46
S8	6	(QIN KELLERMAN).in. and chuck	US-PGPUB	OR	ON	2005/03/03 09:47
S9	3	(QIN KELLERMAN).in. and chuck	US-PGPUB	OR	ON	2005/03/03 09:49
S10	6	(QIN KELLERMAN).in. and chuck	US-PGPUB	OR	ON	2005/03/03 09:49
S11	11	(QIN KELLERMAN).in. and chuck	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:00
S12	106	(electro adj static adj chuck)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:01
S13	6697	(electrostatic adj chuck)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:01

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S14	76	(electro-static adj chuck)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:01
S15	6734	(S12 S13 S14)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:02
S16	10281	(S12 S13 S14 esc)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:02
S17	94	S16 and (chuck same de adj chuck dechuck de-chuck)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 12:31
S18	81	S16 and (chuck same (de adj chuck dechuck de-chuck))	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:07
S19	103	S16 and (chuck same (de adj chuck dechuck de-chuck)) or (clamp same (declamp de-clamp de adj clamp))	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:48
S20	82	S16 and (chuck same (de adj chuck dechuck de-chuck)) or (clamp same (declamp de-clamp de adj clamp)) and "361"/\$.ccls.	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:09
S21	1	S19 and square near wave	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:49
S22	1	S19 and single near phase	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:13
S23	39	S19 and residual	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:50
S24	28	S19 and residual same force	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:14

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S25	10	S19 and residual same force and square	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:50
S26	8	S19 and residual same force and square and layer	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:14
S27	365	S16 and (chuck same (de adj chuck\$3 dechuck\$3 de-chuck\$3)) or (clamp\$3 same (declamp\$3 de-clamp\$3 de adj clamp\$3))	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:49
S28	9	S27 and square near wave	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:49
S29	120	S27 and residual	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:50
S30	17	S27 and residual same force and square	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:51
S31	4	S28 and S29 and S30	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:54
S32	95413	S27 asn square near wave	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:54
S33	9	S27 and square near wave	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:55
S34	6	S33 and dielectric near layer	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:56
S35	4	S33 and leak\$3	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:57

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S36	6	S33 and S34	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:57
S37	3	S35 and S34	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 11:57
S38	188	S16 and leak\$3 with layer	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 12:31
S39	44	S16 and leak\$3 with layer near3 (dielectric insulation)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 12:33
S40	30	S16 and (leaking leakage leaked) with layer near3 (dielectric insulation)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 12:34
S41	43	S16 and (leak leaking leakage leaked) with layer near3 (dielectric insulation)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 12:37
S42	0	S16 and (leak leaking leakage leaked) with layer near3 (dielectric insulation) and square near wave	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 12:38
S43	0	S16 and (leak leaking leakage leaked) with layer near3 (dielectric insulation) and square near2 wave	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 13:56
S44	0	applid adj materials	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 13:57
S45	0	applied adj materials	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 13:57
S46	31204	applied adj materials	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 13:57

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S47	1348	S46 and electrostatic adj chuck	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 14:07
S48	2038	S47 (leak\$3 near dielectric)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 13:59
S49	7	S47 and (leak\$3 near dielectric)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 14:07
S50	6697	electrostatic adj chuck	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 16:51
S51	11	S50 and (leak\$3 near dielectric)	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 14:08
S52	4977	electrostatic adj chuck and surface	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/07 14:13
S53	0	electrostatic adj chuck and surface same toporgaphy	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 15:50
S54	1317	electrostatic adj chuck and surface with dielectric	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 15:53
S55	458	electrostatic adj chuck and surface near dielectric	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 15:51
S56	0	S55 and micromachine	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 15:52
S57	49	electrostatic adj chuck and surface with dielectric with shape	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 15:54

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S58	68	electrostatic adj chuck and surface with dielectric with pattern	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 15:54
S59	36	electrostatic adj chuck and surface with dielectric with pattern and leak\$3	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 15:55
S60	2222	S50 and determin\$5	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 16:52
S61	2	S50 and determin\$5 same square with wave	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 16:55
S62	62	S50 and square with wave	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 16:55
S63	2	S50 and square with wave same parameter	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 16:56
S64	43	S50 and square with wave same voltage	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 17:00
S65	4	S50 and square with wave same voltage and RC near3 time	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/03 17:00
S66	2	"20050057881"	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 16:44
S67	9	Clamping near De-clamping near Semiconductor near Wafers	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 16:45

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S68	57	electrostatic near3 chuck and leak\$5 with dielectric near3 layer	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 09:39
S69	15	S68 and square	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 10:12
S70	30	S68 and residual	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 10:13
S71	15	S68 and residual same force	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 10:21
S72	0	"WO-2005027203.\$did."	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 10:21
S73	0	"WO-027203.\$did."	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 10:22
S74	0	"WO-027203.\$did."	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 10:26
S75	43	("20020173059" "3566959" "4788627" "5103367" "5117121" "5155652" "5325261" "5444597" "5452177" "5583736" "5810933" "5838529" "5880922" "5916689" "5958813" "6077357" "6117246" "6149774" "6215643" "6414834" "6452775").PN.	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 10:27

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S76	21	("20020173059" "3566959" "4788627" "5103367" "5117121" "5155652" "5325261" "5444597" "5452177" "5583736" "5810933" "5838529" "5880922" "5916689" "5958813" "6077357" "6117246" "6149774" "6215643" "6414834" "6452775").PN.	US-PGPUB ; USPAT	OR	ON	2006/02/07 10:27
S77	88	electrostatic adj chuck and surface and polarity same switch\$3	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/07 14:14
S78	39	S77 and residual	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/07 14:14
S79	925	electrostatic same clamp same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 12:57
S80	819	electrostatic same clamping same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 12:49
S81	6	S80 same pulse	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 12:41
S82	3	S80 same pulse same width	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 10:42
S83	6	S80 same pulse	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 12:41

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S84	1332	residual same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 13:52
S85	353	S84 same electrostatic	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 13:51
S86	157	S85 same force	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 13:53
S87	1332	residual same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 13:51
S88	1332	residual same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 13:52
S89	828	residual\$0 adj force\$1	USPAT	OR	ON	2006/02/08 15:52
S90	1111	residual\$0 adj force\$1	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/08 14:59
S91	1110	residual\$1 adj force\$1	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/08 15:08
S92	7989	electrostatic near2 chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 14:59

EAST Search History

S93	965	electrostatic\$1 same clamp\$1 same chuck\$0	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:00
S94	925	electrostatic\$1 same clamp\$1 same chuck\$1	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:02
S95	11	S94 and S91	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:01
S96	8585	electrostatic\$1 same chuck\$1	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:07
S97	925	S94 and S96	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:03
S98	10	S97 and qin.in.	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:19
S99	8585	electrostatic same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:13
S10 0	1110	residual\$1 adj force\$1	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/08 15:08

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S10 1	791	residual adj force	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/08 15:08
S10 2	791	residual adj force	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/08 15:20
S10 3	8371	electrostatic same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 16:40
S10 4	9	S102 same S103	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 15:17
S10 5	17	S102 and S103	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 15:17
S10 6	1	S100 and qin.in.	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:20
S10 7	0	S105 and qin.in.	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:21
S10 8	4026	residual near2 force	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/08 15:21
S10 9	128	S108 and S103	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/08 15:21

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S11 0	4	S109 and qin.in.	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/08 15:51
S11 1	583	residual adj force	USPAT	OR	OFF	2006/02/08 15:53
S11 2	282	residual adj forces	USPAT	OR	OFF	2006/02/08 15:53
S11 3	2	residual near2 clamping adj forces	USPAT	OR	OFF	2006/02/08 16:34
S11 4	5	residual near6 clamping adj forces	USPAT	OR	OFF	2006/02/08 16:35
S11 5	50	residual near6 clamping adj force	USPAT	OR	OFF	2006/02/08 16:35
S11 6	45	residual near2 clamping adj force	USPAT	OR	OFF	2006/02/08 16:39
S11 7	9	S103 and S116	USPAT	OR	OFF	2006/02/08 16:36
S11 8	8	S103 and S116 and dielectric same layer	USPAT	OR	OFF	2006/02/08 16:36
S11 9	8	S103 and S116 and dielectric same layer	USPAT	OR	OFF	2006/02/08 16:38
S12 0	0	S103 and S116 and dielectric same layer same leaky	USPAT	OR	OFF	2006/02/08 16:37
S12 1	0	S103 and S116 and dielectric same layer same leak	USPAT	OR	OFF	2006/02/08 16:37
S12 2	0	S103 and S116 and dielectric same layer and leaky	USPAT	OR	OFF	2006/02/08 16:38
S12 3	0	S103 and S116 and dielectric same leaky	USPAT	OR	OFF	2006/02/08 16:38
S12 4	8	S103 and S116 and dielectric same layer	US-PGPUB ; USPAT; EPO; JPO	OR	OFF	2006/02/08 16:38
S12 5	60	residual near2 clamping adj force	US-PGPUB ; USPAT; EPO; JPO	OR	OFF	2006/02/08 16:39
S12 6	60	residual near2 clamping adj force	US-PGPUB ; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2006/02/08 16:39

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S12 7	14	S103 and S126	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 16:40
S12 8	14	S103 and S126 and dielectric	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 16:40
S12 9	240519	(dielectric same layer)	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 16:41
S13 0	13	(dielectric same layer) and S127	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 16:42
S13 1	1	(dielectric same layer same (leak leaking leaky)) and S127	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 16:42
S13 2	1	(dielectric same layer same (topography)) and S127	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/08 16:43
S13 3	719	electrostatic same clamp same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/09 09:26
S13 4	927	electrostatic same clamp same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/09 09:26

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S13 5	8382	electrostatic same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/09 09:26
S13 6	8596	electrostatic same chuck	US-PGPUB ; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/09 09:26
S13 7	791	residual adj force	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/09 09:26
S13 8	1106	residual adj force	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/09 09:27
S13 9	19	S136 and S138	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/09 10:35
S14 0	18	S136 and "j-r"	US-PGPUB ; USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/09 10:35
S14 1	12	S136 and "j-r"	USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/09 10:37
S14 2	96	S136 and ("j-r" "Johnsen-Rahbek")	USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/09 10:38
S14 3	2	S142 and S138	USPAT; EPO; JPO; DERWENT	OR	ON	2006/02/09 10:38